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van de Grift, R.; Rutten, I.W.J.M.; van der Veen, M.;
Solid-State Circuits, IEEE Journal of , Volume: 22 , Issue: 6 , Dec 1987
Pages:944 - 953

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Wai Yuen Lau;

Electronics Manufacturing Technology Symposium, 2002. IEMT 2002. 27th Annual IEEE/SEMI International, 17-18 July 2002

Pages:353 - 359

[\[Abstract\]](#) [\[PDF Full-Text \(822 KB\)\]](#) IEEE CNF
2 Integrated probe card/interface solutions for specific test applications

Anderson, J.;

Test Conference, 1998. Proceedings. International, 18-23 Oct. 1998

Pages:282 - 283

[\[Abstract\]](#) [\[PDF Full-Text \(176 KB\)\]](#) IEEE CNF
3 Proceedings International Test Conference 1998 (IEEE Cat. No.98CH36270)

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4 A self-test system architecture for reconfigurable WSI

Landis, D.L.;

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Zargari, M.; Leung, J.; Wong, S.S.; Wooley, B.A.;
Solid-State Circuits, IEEE Journal of , Volume: 34 , Issue: 8 , Aug. 1999
Pages:1118 - 1135

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**6 Hardware for production test of RFID interface embedded into chip:
smart cards and labels used in contactless applications**

da Costa, C.;

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7 RF (gigahertz) ATE production testing on wafer: options and tradeo

Gahagan, D.A.;

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